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SIMPLE TECHNIQUE FOR SOURCE REFLECTION COEFFICIENT MEASUREMENT WHILE CHARACTERIZING ACTIVE DEVICES

Andrea Ferrero and Gian Luigi Madonna
Dipartimento di Elettronica, Politecnico di Torino
Corso Duca degli Abruzzi, 24, 10129 Torino, Italy
Tel. +39-11-564 4082. Fax +39-11-564 4099. E-mail: ferrero@polito.it

ABSTRACT

This paper describes a simple, yet rigorous technique for fast and accurate determination of the source reflection coefficient during the characterization of microwave active devices. The solution consists in measuring the waves at the DUT reference plane under two different bias conditions. Since the DUT small signal impedance value depends on the bias voltage, the waves at the DUT input port changes as well. We proved that their measurements give enough information to compute the source reflection coefficient with accuracy suitable for most applications. The correction for systematic errors is based in the traditional error-box model and it does not require any exotic calibration procedures. Experimental results are presented and compared to data obtained with more traditional techniques.

PROBLEM DEFINITION

Microwave source-pull measurement techniques consist in monitoring the desired performance of the device under test (DUT) while driving it with different source impedance values. This approach is widely used for microwave active device characterization, both in small and large signal conditions. A typical application is low noise amplifier (LNA) design to experimentally obtain the optimum noise impedance [1] or the matching network for mixers, oscillators and high efficiency amplifiers [2 - 5].

Figure 1 shows the simplified block scheme of a traditional test-set for both source and load-pull characterization of active devices. Two reflectometers measure the waves at the DUT reference planes, while two tuners set the source and load conditions at the input and output ports, respectively. Traditional measurement systems are able to obtain calibrated values of \( a_1 \) and \( b_1 \) and their ratio

\[
\Gamma_m = \frac{b_1}{a_1} \tag{1}
\]

On the other side, the source reflection coefficient \( \Gamma_s \) is defined as

\[
\Gamma_s = \frac{a_s}{b_1} \left(1 - \frac{a_s}{a_t}\right) \tag{2}
\]

Obviously \( \Gamma_s \) it is equal to ratio \( a_s/b_1 \) only if \( a_t = 0 \), i.e. the internal generator is switched off.

A simple technique for measuring \( \Gamma_s \) is suggested in [6] for not unilateral DUT (i.e. \( s_{12} \neq 0 \)). First, the DUT is excited from port 1 and its input gamma is computed by eq.(1). Then, the source signal is turned to port 2 and a second acquisition of waves \( a_1, b_1 \) is performed. From (2), the source reflection coefficient is simply the ratio \( \Gamma_s = a_s/b_1 \), since now the source term \( a_s \) is null.

A completely different approach is described in [1].

![Fig.1. Simplified block scheme of a traditional test-set for both source and load-pull characterization of active devices.](image-url)
where the reflection coefficient of the tuning element is continuously monitored by a six-port reflectometer in reverse configuration. This technique is both accurate and suitable for automatic source pulling; however, the problem is just diverted, since now it is the DUT reflection coefficient $\Gamma$ that cannot be determined.

The method presented in [7] solves the latter problem. The microwave signal is first injected before the reflectometer to measure the DUT input characteristic; then, it is switched immediately after, in order to measure the source reflection coefficient in the reverse configuration.

Common feature of all the previous approaches is that they measure the DUT and the source reflection coefficients by two different steps, and they involve switching the microwave source signal. For fast and automatic characterization of active devices, this can be time consuming. The authors recently proposed a new technique based on the concept of a three-sampler reflectometer [8], which allows the simultaneous determination of source and DUT input gamma. This technique is indeed fast and accurate, but it is based on unconventional error model and it requires a special purpose calibration procedure.

**NOVEL SOLUTION**

The solution here proposed is a simple, yet rigorous technique for determining the source reflection coefficient while characterizing active devices. Briefly, it consists in measuring waves $a_1, b_1$ at the DUT input reference plane under two different DUT bias conditions (obtaining $a_1', b_1'$ and $a_1'', b_1''$). Assuming that neither the source signal $S_a$ nor $S_\Gamma$ changes in the two situations, two equations like (2) are stacked to form a simple linear system in the unknowns $S_a, S_\Gamma$. Its solution gives

\[
\Gamma_s = \frac{a_1' - a_1''}{b_1'' - b_1'} \quad (3)
\]

The novel technique has some noteworthy features:
- it is rigorous, since it is not based on the repeatability of a microwave source switch;
- it is safe and suitable for source and load pull characterization of unilateral devices, since it does
not require to excite the DUT back from port 2 (as required in [6]);
• it is flexible, since it can be successfully applied to different source pull test-set configurations;
• the correction for systematic errors is based on the traditional error-box model and it does not require any exotic calibration procedures.

The technique was successfully applied to measure the source reflection coefficient during harmonic load-pull HEMT characterization. A commercial 0.5-18 GHz active load-pull system was used, as shown in figure 2. The measurement setup is based on a traditional vector network analyzer, used as a four-channel microwave receiver. A passive tuner set the source reflection coefficient. Vector corrected waves at the DUT input port were obtained by the same calibration procedure already implemented in the system software. Figure 3 shows some experimental results obtained by the new method and the technique described in [6].

CONCLUSIONS

A novel technique has been presented to measure the reflection coefficient of the microwave source while characterizing active devices. Due to its simplicity, the technique is an interesting solution that can be applied in several situations. The accuracy experimentally shown against traditional methods is sufficient for most of applications.

REFERENCES